



Vertical Emittance Measurements using a Vertical Undulator

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Australian Synchrotron

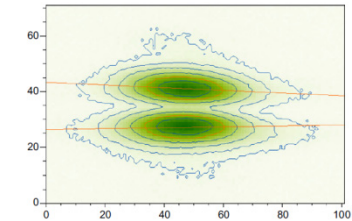
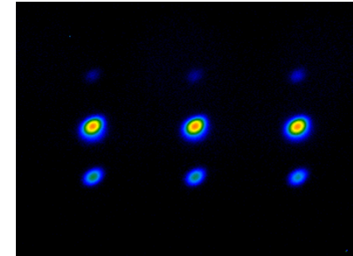
Y. Papaphilippou

CERN

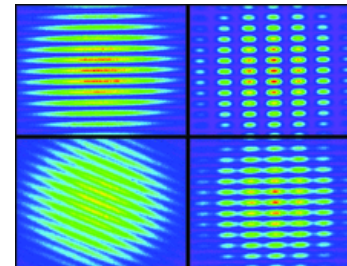
- Collider damping rings and Super B-factory storage rings demand $\varepsilon_y = 0.5\text{-}2.0$ pm rad
- Collective effects lead to growth
 - Intra-beam scattering, electron cloud
- Storage ring light sources as test accelerators
 - SLS, ATF2, CESR, ASLS, Diamond, ...
- Need measurements of vertical emittance

Synchrotron light vertical emittance monitors

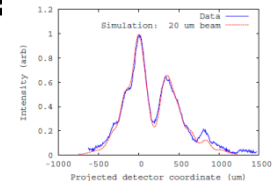
- Three main approaches:
 - Imaging
 - Interferometry
 - Projection
- Quick diagnostic of storage ring
- Typically bending magnet
 - $\$ \$ \downarrow, \beta_y \uparrow, \eta_x \downarrow$
- Visible light, hard x-ray



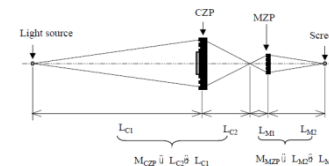
Andersson, NIMA 591, 437-446 2008



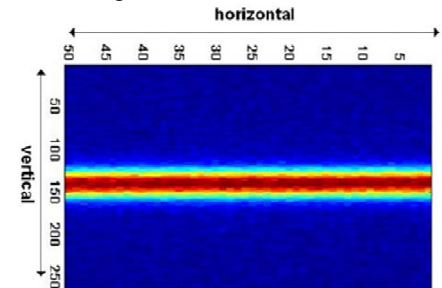
Masaki DIPAC01, PS17



Flanagan PAC09, TH5RFP048

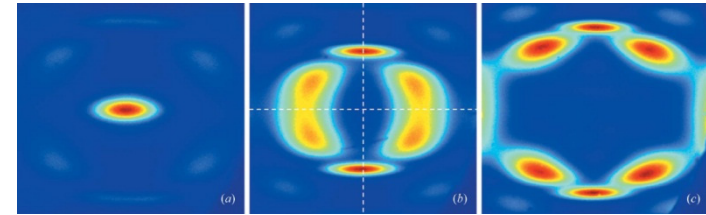


Nakamura PAC01, TPAH307

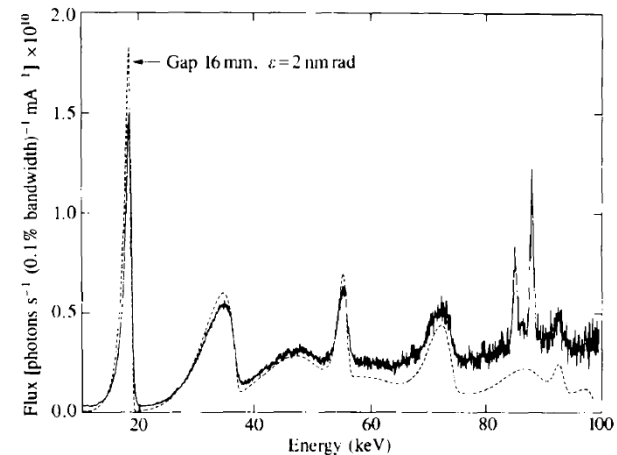


Scheidt, DIPAC05 CTWM01

- Focus on odd (useful!) harmonics
- **Horizontal undulators**
 - Imaging
 - Projection
 - Absolute spectral brilliance (pinhole flux)
- Energy spread, dispersion, 'large' emittance



Moreno JSR, 19 179-84 (2012)

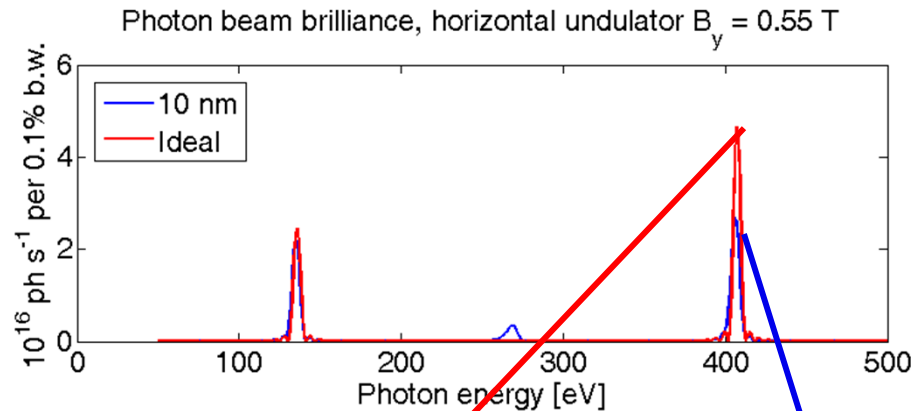


Hahn JSR 4, 1-5 (1997)

Undulator beam projection

Horizontal
Undulator
25 periods
75 mm period
 $K = 3.85$

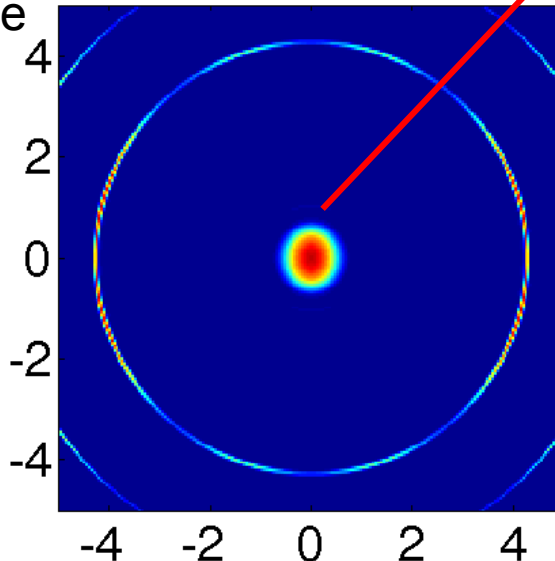
Pinhole
50 x 50 μm
15m distance



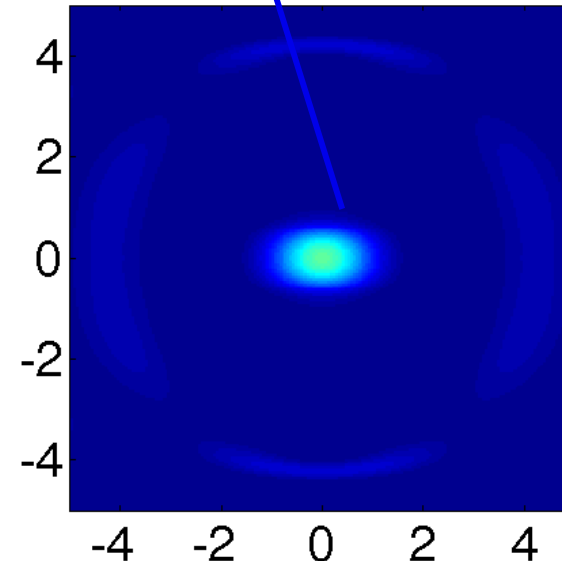
Electron beam

$$\begin{aligned}\varepsilon_x &= 10 \text{ nm} \\ \varepsilon_y &= 100 \text{ pm} \\ \sigma_E &= 0.11\%\end{aligned}$$

Ideal emittance

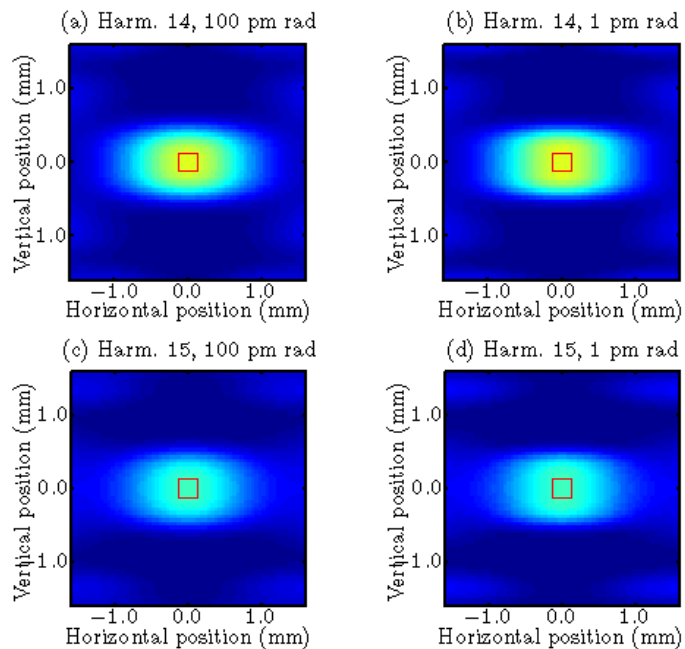


Normal emittance

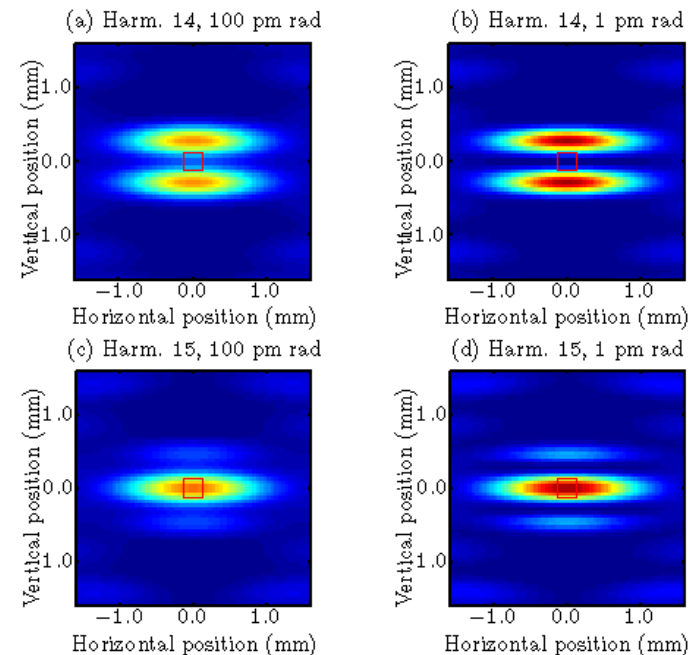


Tanaka & Kitamura, JSR 8 1221 (2001)

Horizontal undulator



Vertical undulator

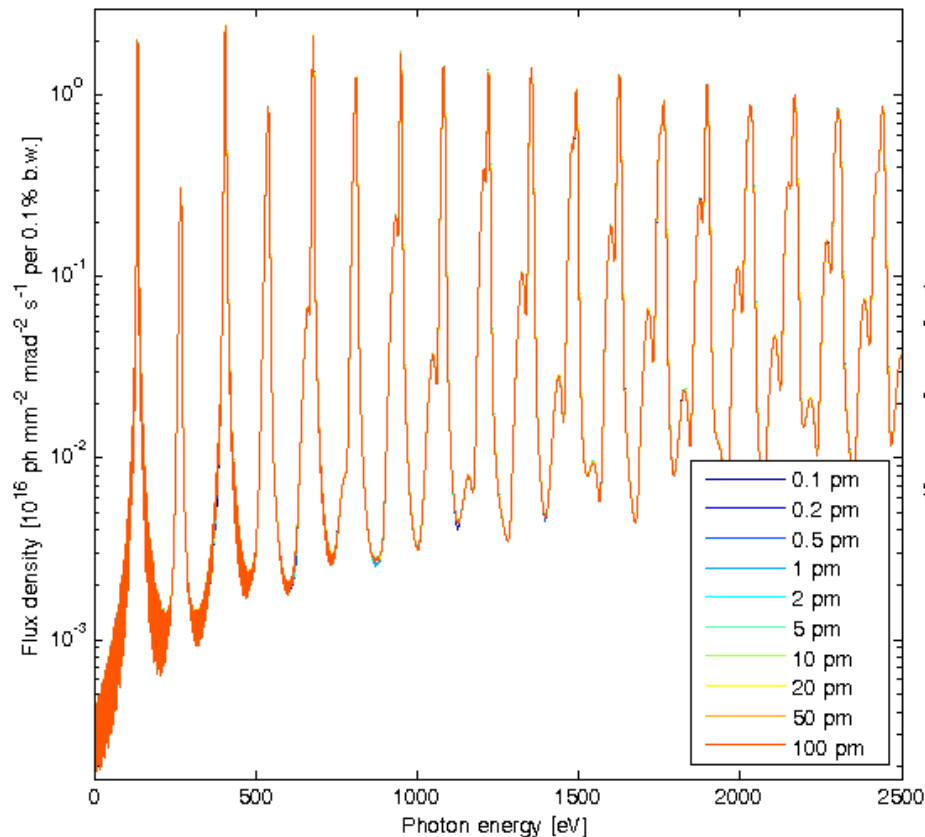


Undulator
25 periods
75 mm period
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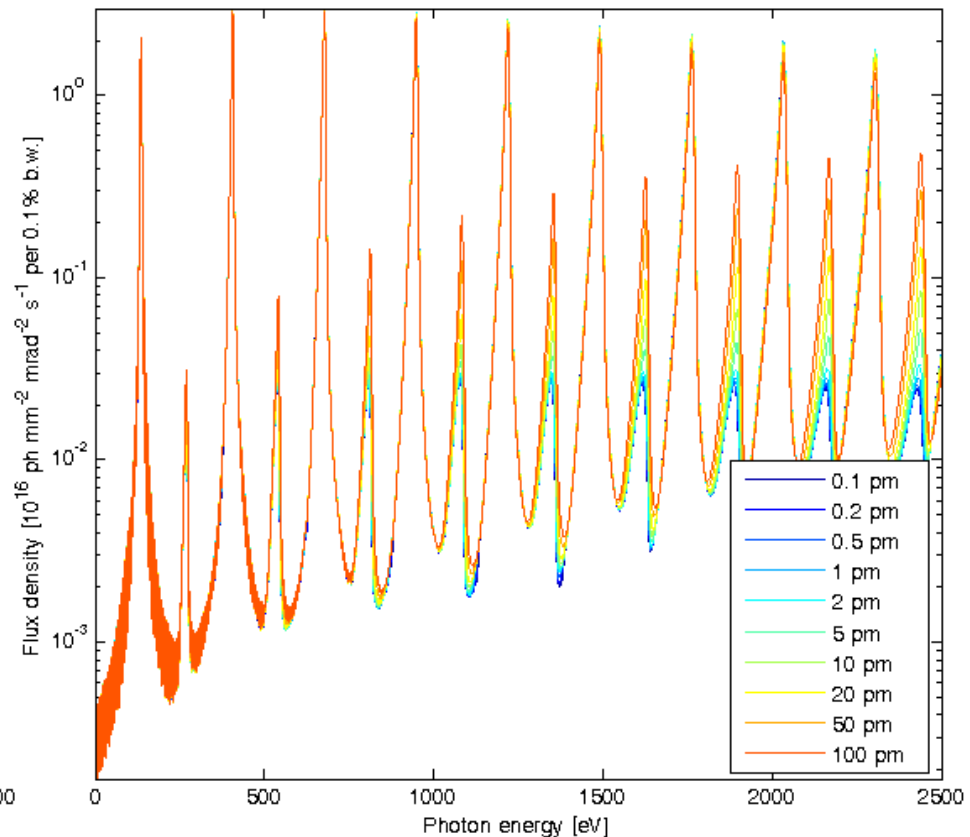
Electron beam
 $\varepsilon_x = 10 \text{ nm}$
 $\varepsilon_y = 100 \text{ pm}$
 $\sigma_E = 0.11\%$

Photon beam brilliance

- Horizontal undulator
 - No contrast

Photon beam brilliance, horizontal undulator $B_x = 0.55$ T

- Vertical undulator
 - Even harmonics

Photon beam brilliance, vertical undulator $B_y = 0.55$ T

- ‘It is evident that the second-harmonic brightness is proportional to the beam emittance ...’
Dattoli PRE 52(6) 6809-17 (1995)
- I add to this: ... the emittance in the direction of undulations
 - How do we measure photon beam brilliance?

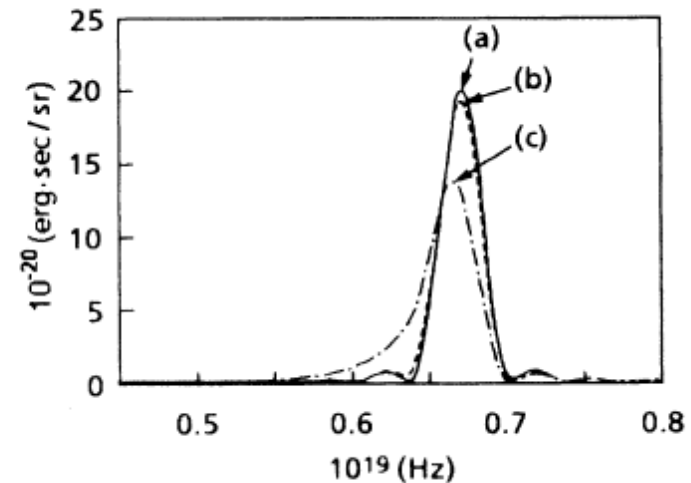
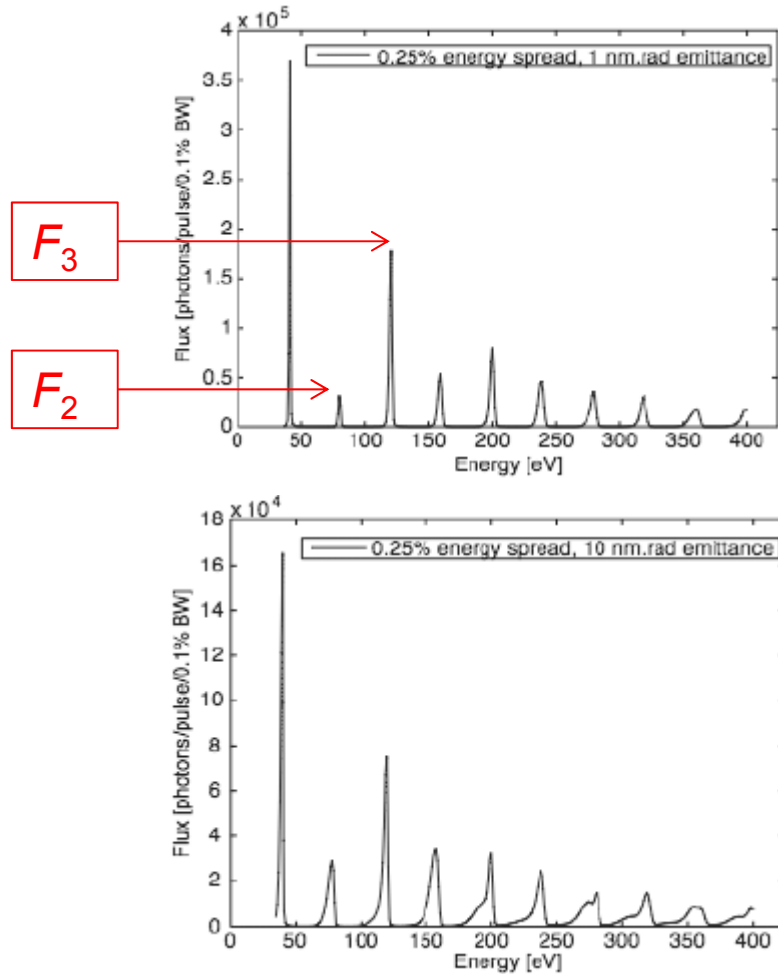


FIG. 1. First-harmonic brightness vs frequency parameters

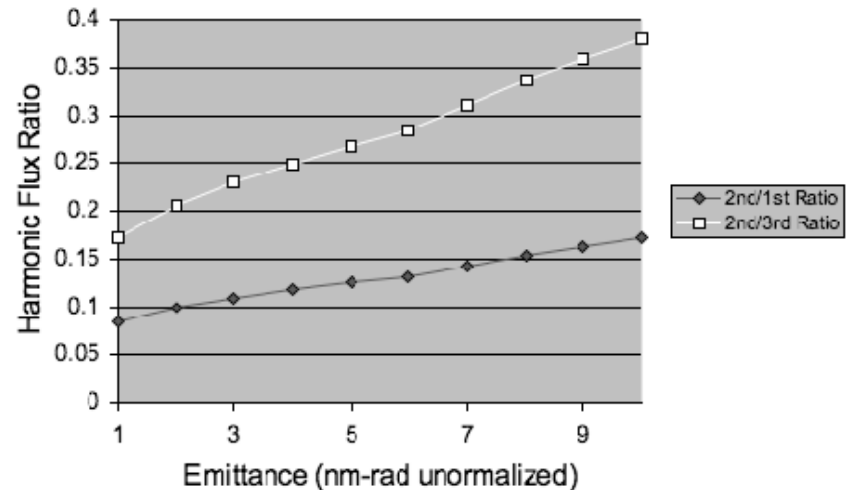
Dattoli PRE 52(6) 6809-17 (1995)

Pinhole flux ratio

- Electron wakefield accelerator
- Flux ratio F_{n-1} / F_n



Flux Ratio vs. Emittance

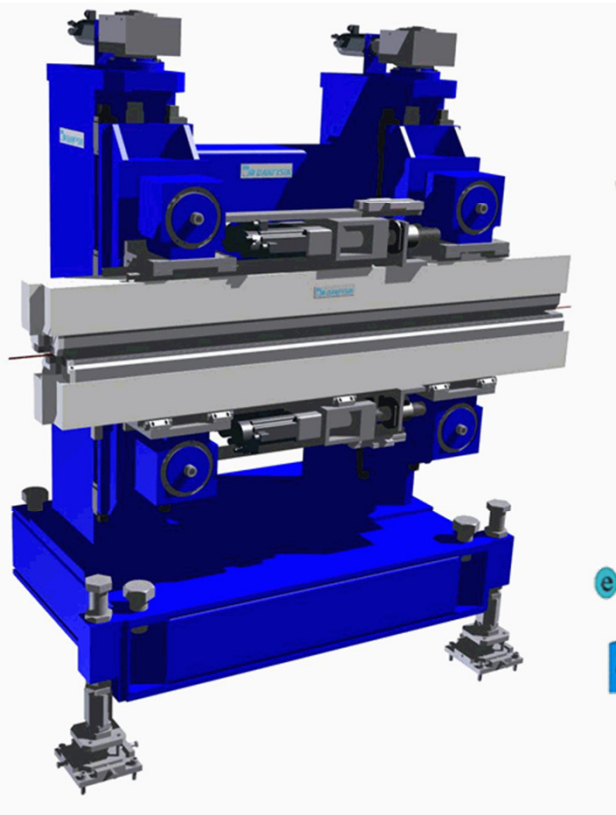


M. Bakeman et al., PAC 2009, WE6RFP074

M. Bakeman, et al., PAC 2011, MOP161

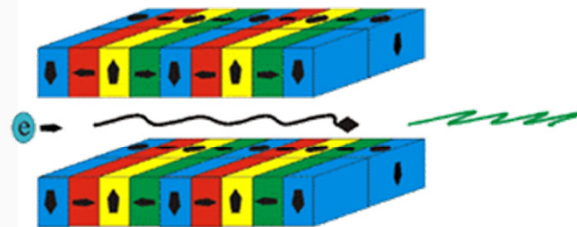
Advanced Planar Polarised Light Emitter-II

Modes of operation



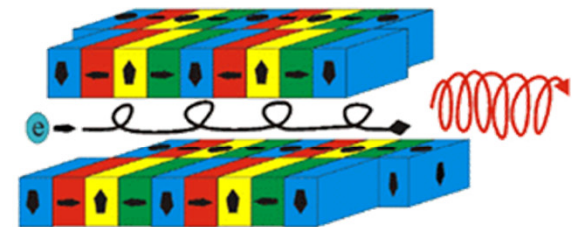
1. mode: linear horizontal polarization

Linear: $S_1=1$ Shift=0



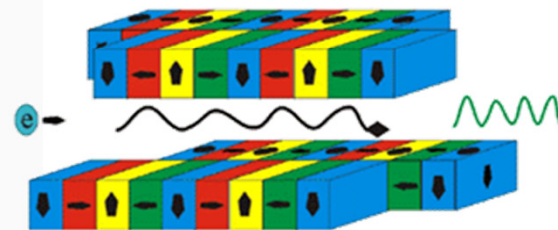
2. mode: circular polarization

Circular: $S_3=1$ Shift= $\lambda/4$

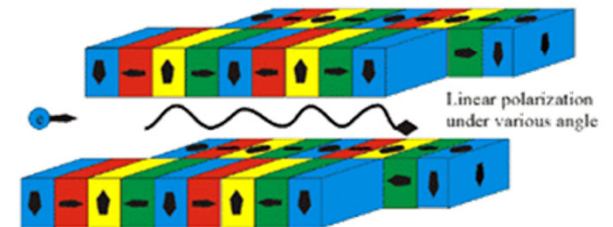


3. mode: vertical linear polarization

Linear: $S_1=-1$ Shift= $\lambda/2$



4. mode: linear polarization under various angle
shift of magnetic rows antiparallel



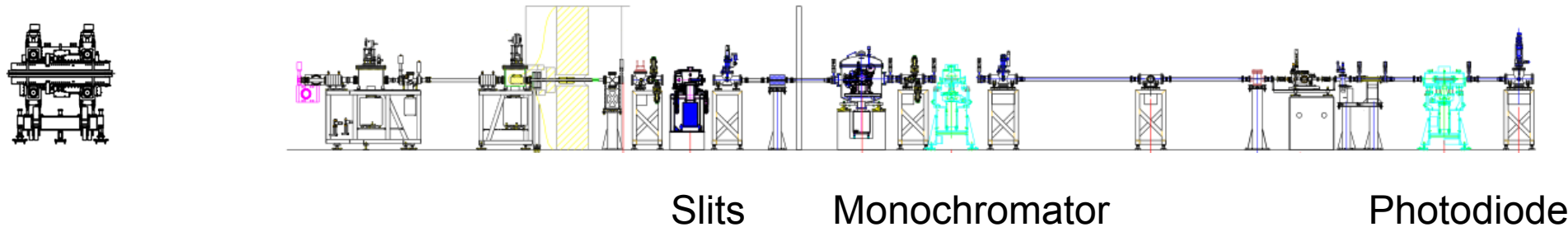
Sasaki, Nucl. Instrum. Methods A **347**, 83 (1994)

Soft x-ray undulator beamline

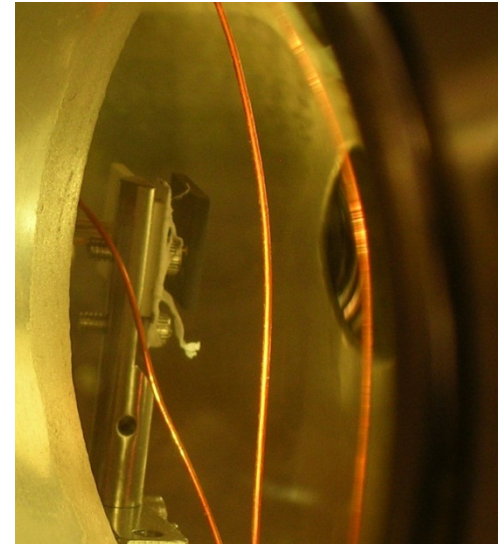


Soft x-ray undulator beamline

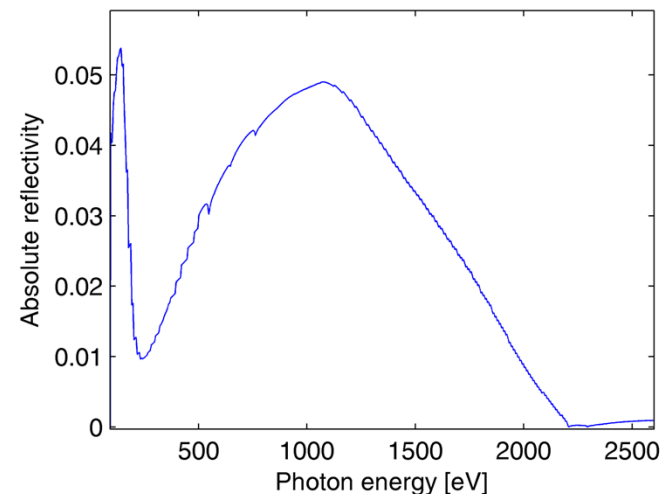
- APPLE-II undulator
- White beam slits first optical element
- All focussing, monochromator downstream



- Measuring vertical emittance with one large pixel!
 - Beamline optics
 - Grating monochromator
 - Au-coated mirrors
 - Energy-defining slit
 - Photodiode (GaAsP, Si)
- B.C.C. Cowie, et al., AIP Conf. Proc. 1234, 307 (2010)
- Au-coated mirrors
 - Transmission varies with photon energy



Beamline optics reflectivity



- Early experiments
 - Hamamatsu GaP/Au
- Ratio of peaks
- Absorption edges
 - Silicon photodiode
- Keithley picoammeter
 - Spans many orders of magnitude in current

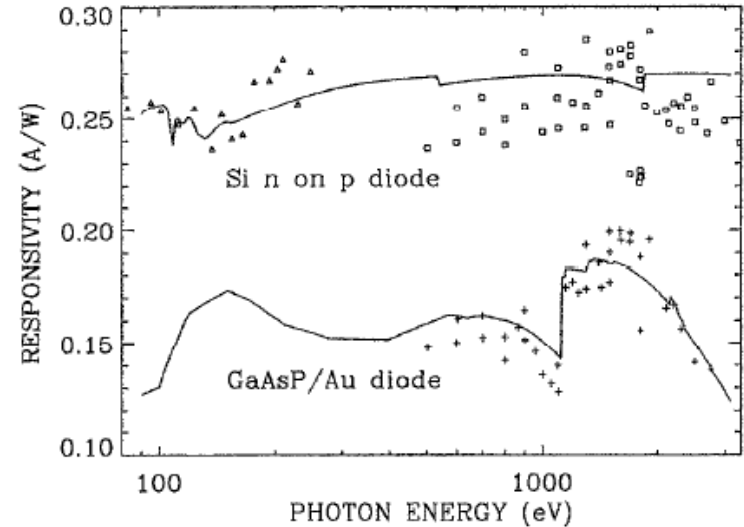


FIG. 2. Spectral responsivity of a Si *n* on *p* diode and a GaAsP/Au diode

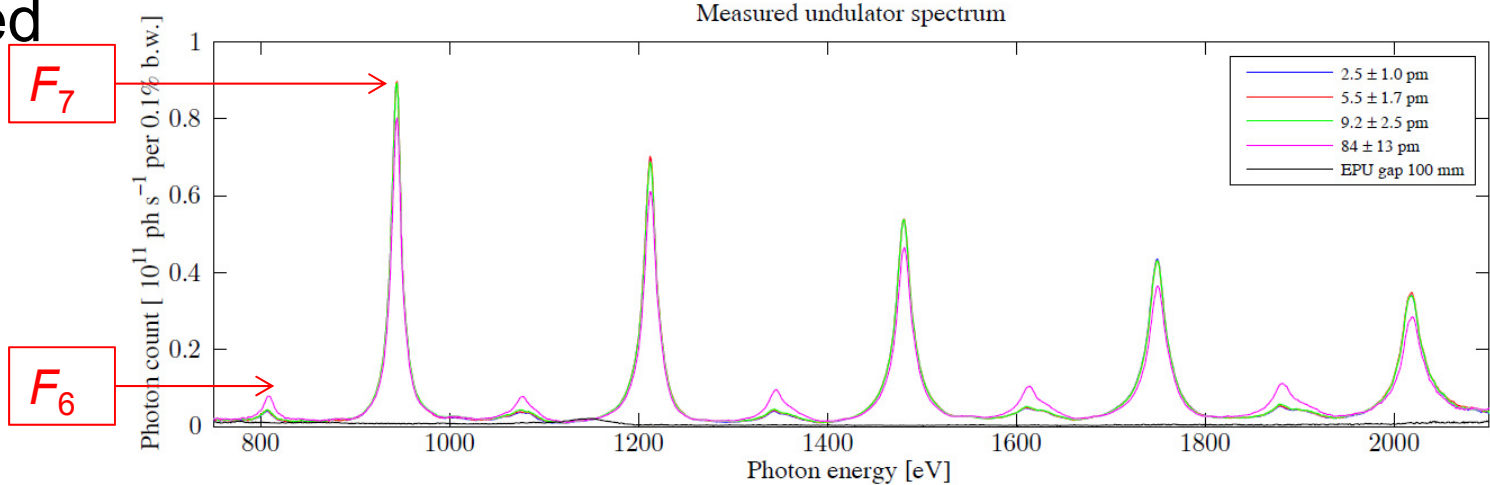
Krumrey, Tegeler (1992)
Rev Sci Instrum 63 (1), p.
797-801

Measured undulator spectrum

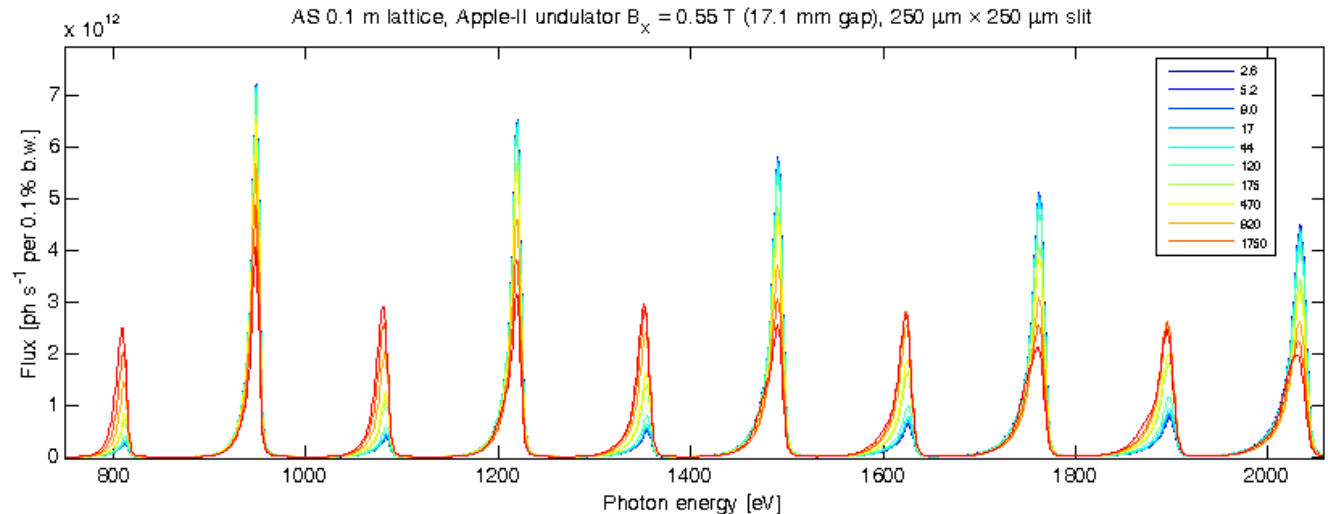
- Measured

Flux ratio

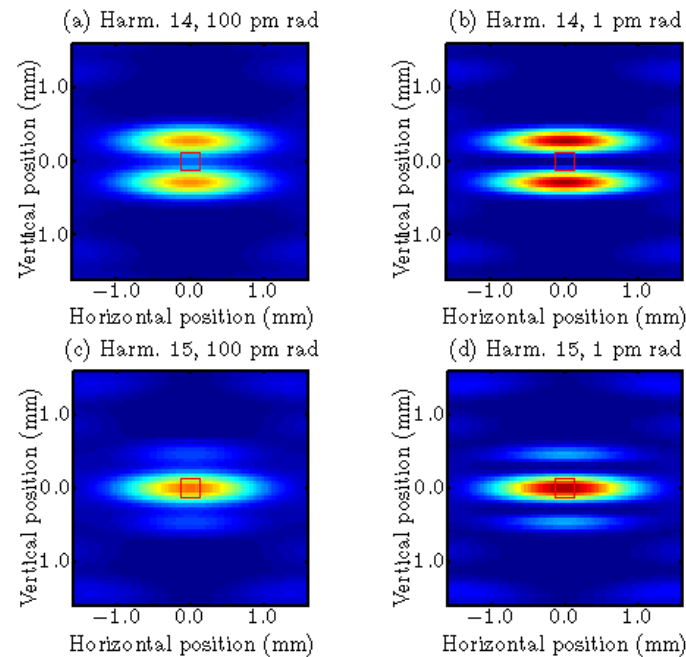
$$F_{n-1} / F_n$$



- Modelled



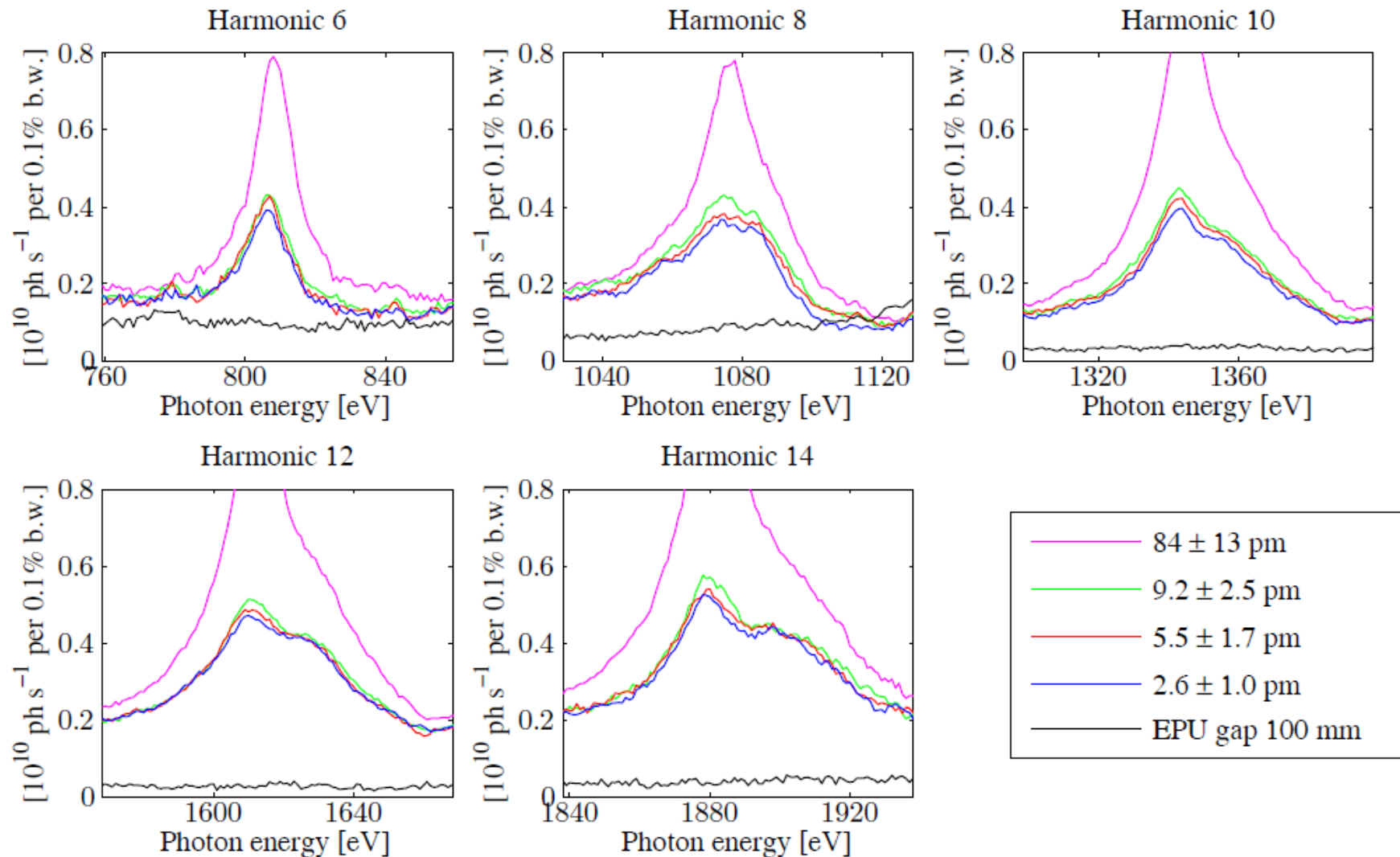
Vertical undulator



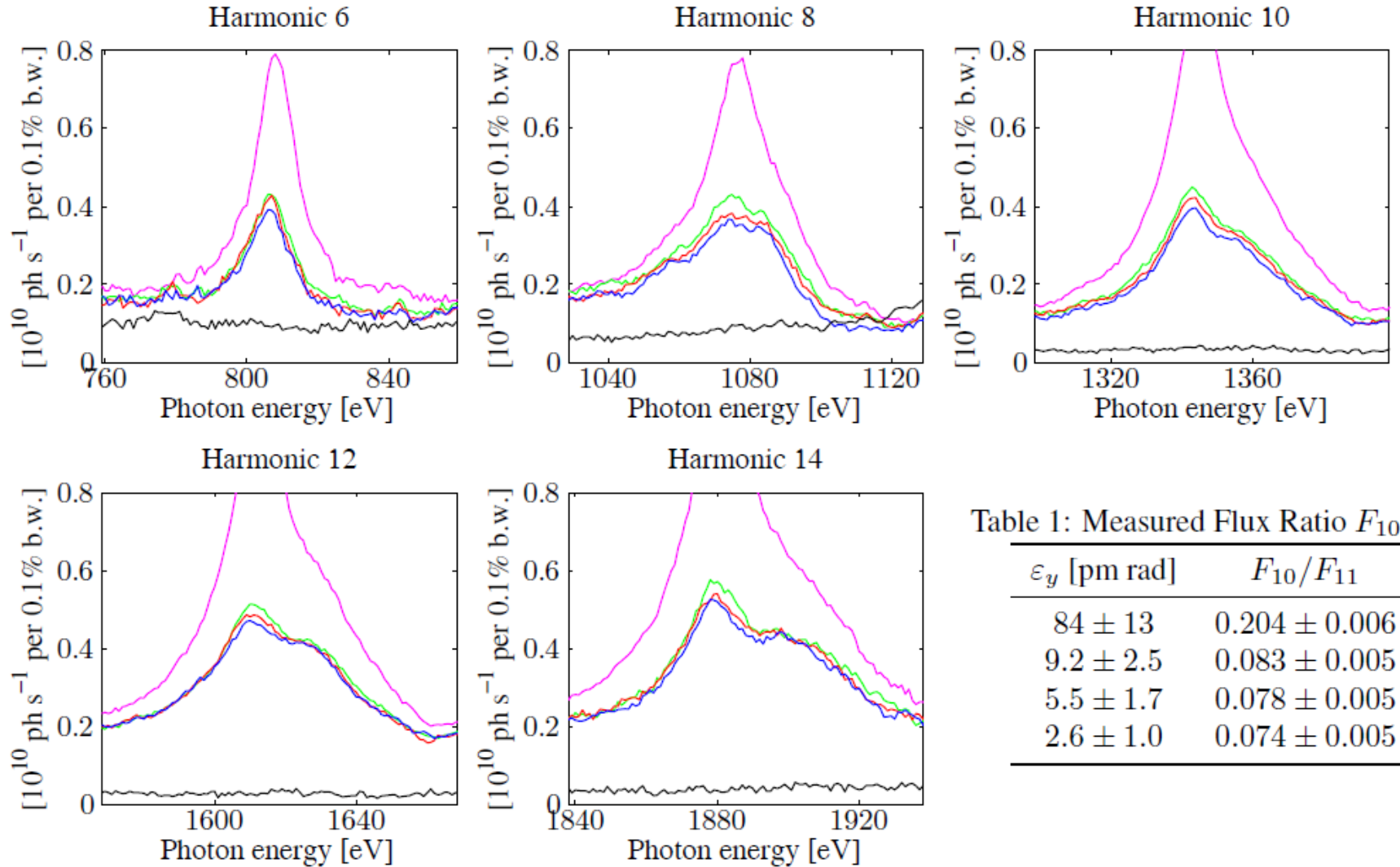
Undulator
25 periods
75 mm period
 $K = 3.85$

Electron beam
 $\varepsilon_x = 10 \text{ nm}$
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 $\sigma_E = 0.11\%$

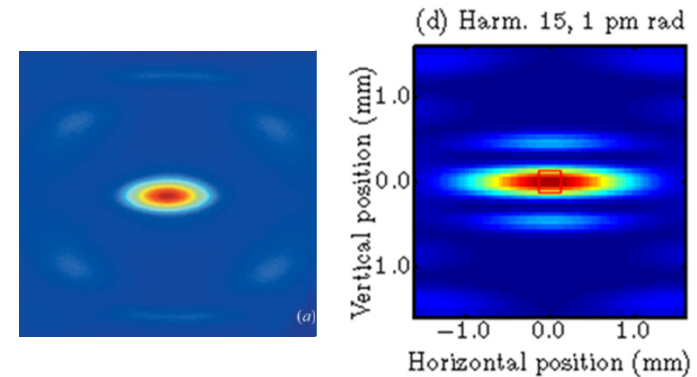
Even harmonics



Even harmonics



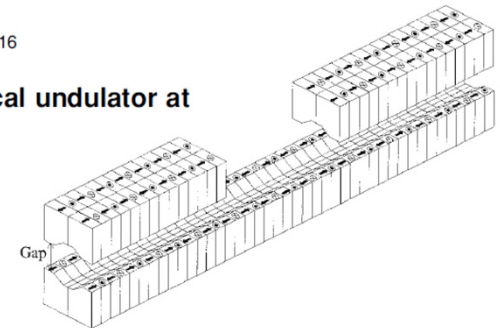
- Fixed pinhole diameter
- SOLEIL DiagOn (fixed energy 367.5 eV)
- SPring-8 BL45XU (vertical IVU)
- Higher undulator K



Moreno JSR, 19 179-84 (2012)

J. Synchrotron Rad. (1998), 5, 414–416

Construction of a vertical undulator at
SPring-8



Tanaka JSR 5, 414 (1998)

- Undulator measurement of emittance is an old technique
 - Usually use horizontal undulator, horizontal emittance
 - Introduce vertical undulator, vertical emittance
- Measure pinhole spectra for different emittances
 - Pinhole much smaller than $1/\gamma$ undulator cone.
- Evaluate ratios of adjacent harmonics
 - Simulations of undulator flux
 - Knowing pinhole size, would fit for beam emittance
- New vertical emittance measurement for many electron storage rings



Australian
Synchrotron
Turning bright ideas into brilliant outcomes



Agilent Technologies

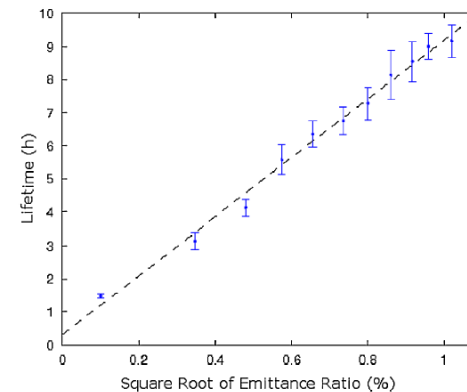
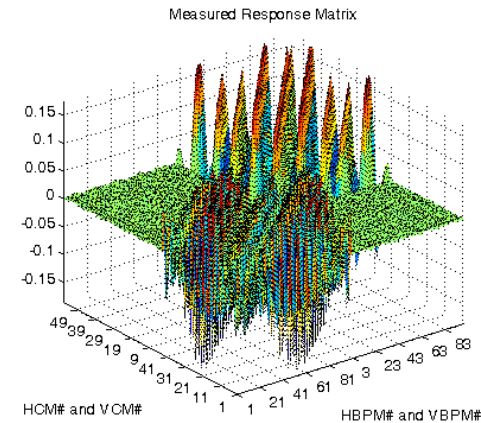
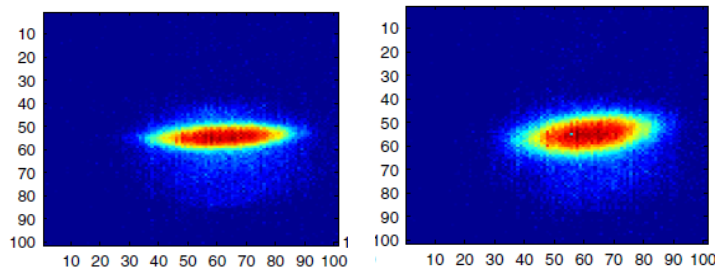


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- Åndersson, NIMA 591, 437-446 (2008)
- Bakeman, et al., PAC 2009, WE6RFP074
- Bakeman, et al., PAC 2011, MOP161
- Boogert PRSTAB 13, 122801 (2010)
- Cowie, et al., AIP Conf. Proc. 1234, 307 (2010)
- Dattoli PRE 52(6) 6809-17 (1995)
- Dowd, et al., PRSTAB 14, 012804 (2011)
- Flanagan PAC09, TH5RFP048
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- Masaki DIPAC01, PS17
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- Sasaki, NIM:A 347, 83 (1994)
- Scheidt, DIPAC05 CTWM01
- Shintake NIM:A 311, 453-464 (1992)
- Tanaka, et al., JSR 5, 414 (1998)
- Tanaka & Kitamura, JSR 8 1221 (2001)



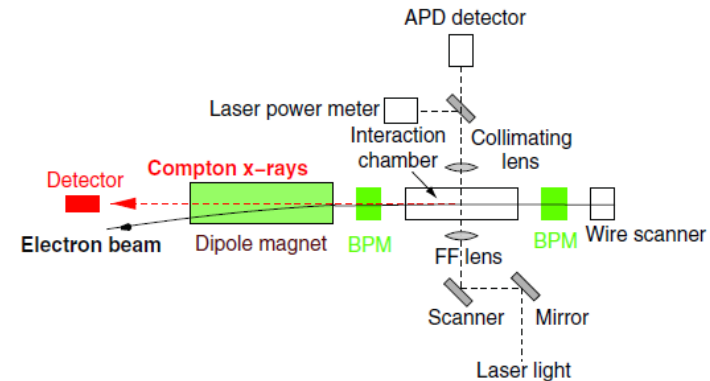
- Orbit response matrix fitting
- Touschek lifetime
 - Eigen as opposed to projected emittances
- Beam ellipse tilt (bending magnet)



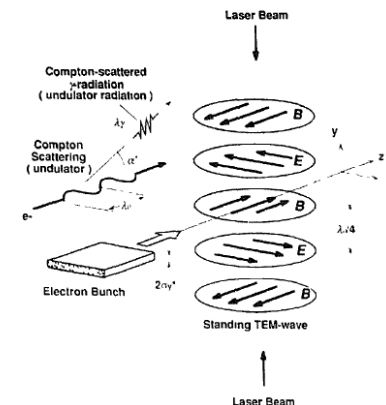
Dowd PRSTAB
14, 012804 (2011)

Direct measurement Laser wire scanner

- Scanning laser waist through electron beam
 - Inverse Compton gamma rays
- Shintake monitor
 - Interference pattern narrower than laser waist



Boogert PRSTAB 13, 122801 (2010)



Shintake NIMA 311, 453-464 (1992)